









Tutorial: Beam Diagnostics ARD ST3 Annual Meeting October 2019 GSI Darmstadt, 18th of October 2019 Peter Forck, GSI

October 18th, 2019 ARD ST3 Annual Meeting <u>GSI, Darms</u>tadt





Standard instrumentation is discussed only!

Some hints to recent developments & comparison electron ↔ proton instrumentation. Laser wake-field accelerators are not covered.

General usage of beam instrumentation:

- > Monitoring of beam parameters for operation, beam alignment & accelerator development
- Instruments for automatic, active beam control e.g. orbit feedback

Non-invasive (= 'non-intercepting' or 'non-destructive') methods are preferred:

- \blacktriangleright The beam is not influenced \Rightarrow the **same** beam can be measured at several locations
- The instrument is not destroyed due to high beam power by proton beams

Non-scanning, 'single shot' methods are preferred: Beam fluctuations at LINACs are visible Observation during entire cycle are preferred: Consistent beam evolution visible at synchr.

General tendencies:

- Electron accelerator: High spatial &temporal resolution due to small beams, short pulses
- ➢ Proton & ion accelerator: Non-invasive methods due to high beam power, radiation hardness long pulses t_{pulse} ≫ 1 µs (except for laser-wakefield acceleration)

Both: High accuracy required to critical beam setting

Topics of this tutorial:

- Beam current and bunch charge by transformers
 - 1. Broadband, 'fast' current transformer FCT
 - 2. dc current transformer DCCT e.g. for synchrotron
 - 3. Integrating current transformer ICT for short pulse at LINAC-FELs
- Beam center-of-mass by Beam Position Monitors BPM
- Transverse profile measurement techniques
- Longitudinal profile = bunch shape measurement





Magnetic field of the beam and the ideal Transformer

> Beam current of N_{part} charges with velocity β $I_{beam} = qe \cdot \frac{N_{part}}{l} = qe \cdot \beta c \cdot \frac{N_{part}}{l}$ > cylindrical symmetry magnetic field B at radius r: $B \sim 1/r$ \rightarrow only azimuthal component $\overrightarrow{B} \parallel \overrightarrow{e}_{0}$ $\vec{B} = \mu_0 \frac{I_{beam}}{2\pi r} \cdot \vec{e_{\varphi}}$ Example: $I = 1 \mu A$, $r = 10 \text{ cm} \Rightarrow B_{beam} = 2 \text{ pT}$, earth $B_{earth} = 50 \mu T_{beam \text{ current I}}$ Idea: Beam as primary winding and sense by sec. winding. \Rightarrow Loaded current transformer $I_1/I_2 = N_2/N_1 \Rightarrow I_{sec} = 1/N \cdot I_{beam}$ \succ Inductance of a torus of μ_r Torus to guide the magnetic field $L = \frac{\mu_0 \mu_r}{lN^2} \cdot lN^2 \cdot \ln \frac{r_{out}}{lN^2}$ 2π r_{in} > Goal of torus: Large inductance **L** Ibean Vout and guiding of field lines. Definition: $U = L \cdot dI/dt$



Simplified electrical circuit of a passively loaded transfor





Equivalent circuit for analysis of sensitivity and bandwidth (without loss resistivity R_L)



A voltages is measured:

 $U = R \cdot I_{sec} = R / N \cdot I_{beam} \equiv S \cdot I_{beam}$ with *S* sensitivity [V/A], equivalent to transfer function or transfer impedance *Z*

courtesy Company Bergoz



U(t)

Time domain description:

Droop time: $\tau_{droop} = 1/(2\pi f_{low}) = L/R$ Rise time: $\tau_{rise} = 1/(2\pi f_{high}) = 1/RC_s$ (ideal without cable Rise time: $\tau_{rise} = 1/(2\pi f_{high}) = \sqrt{L_s}C_s$ (with cables) R_L : loss resistivity, R: for measuring.



 \Rightarrow No transformation of dc-signals

Baseline: $U_{base} \propto 1 - \exp(-t/\tau_{droop})$ **positive** & **negative** areas are equal

simplified equivalent circuit

I-source

represents

R

Example for Fast Current Transformer

For bunch beams e.g. during accel. in a synchrotron typical bandwidth of 2 kHz < f < 1 GHz \Leftrightarrow 10 ns < t_{bunch} < 1 µs is well suited Example GSI type:

Inner / outer radius	70 / 90 mm
Permeability	$\mu_r \approx 10^5$ for f < 100kHz $\mu_r \propto 1/f$ above
Windings	10
Sensitivity	4 V/A for R = 50 Ω
Droop time $\tau_{droop} = L/R$	0.2 ms
Rise time $\tau_{rise} = \sqrt{L_S C_S}$	1 ns
Bandwidth	2 kHz 500 MHz



Fast extraction from GSI synchrotron:



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Rise time $\tau_{rise} = \sqrt{L_S C_S}$	1 ns
Bandwidth	2 kHz 500 MHz

mmmm

90

injection



Example: U^{73+} from 11 MeV/u (β = 15 %) to 350 MeV/u



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Revolutions in SIS18 [10³]

30

0,10

0,08

0,06

0,04

0

RMS bunch length [µs]

FCT

Longitudinal Bunch Diagnostics inside Synchrotron by FCT



Acceleration and bunch 'gymnastics' are performed **inside** synchrotrons Bunch shaping for fast, single turn extraction

Example: Bunch merging at upper flattop using 2 cavities at GSI synchrotron Beam: 10⁹ U⁷³⁺ at 600 MeV/u, FCT

Example: 'Bunch compression' prior to extraction Beam: U⁷³⁺ at 300 MeV/u at GSI synchrotron



Further application: Input for cavity regulation loop

Remark: At synchrotron light sources, bunch shape by streak camera recording synchrotron light. Example shown in talk by J.G. Hwang for BESSY-VSR

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Task of the shield:

- > The image current of the walls have to be bypassed by a gap and a metal housing.
- \succ This housing uses μ -metal and acts as a shield of external B-field
 - (remember: I_{beam} = 1 µA, r = 10 cm \Rightarrow B_{beam} = 2pT, earth field B_{earth} = 50 µT)





The dc Transformer DCCT

A single transformer needs varying beam \rightarrow DCCT: The trick is to 'switch two transformers'!

How to measure the DC current? The current transformer discussed sees only B-flux *changes*.





The dc Transformer

Working principle:

Modulation without beam:

Typ. 9 kHz modulation to *B*-saturation \Rightarrow **no** net flux

- Modulation with beam:
 - Saturation reached at different times \Rightarrow net flux
- Net flux: Double frequency than modulation
- Feedback: Compensating current for large sensitivity
- Two magnetic cores: Must be very similar.

Resolution: $I_{min} \approx 1 \ \mu A$ at 100 Hz Reason: Noisy orientation change of magnetic domain called Barkhausen noise

Remark: Same principle used for power suppliers





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Torus radii	r _i = 135 mm r _o =145 mm
Torus thickness	d = 10 mm
Torus permeability	$\mu_{\rm r} = 10^5$
Saturation inductance	B _{sat} = 0.6 T
Number of windings	16 for mod.& sens. ,12 for feedback
Resolution	I ^{min} _{beam} = 2 μA
Bandwidth	$\Delta f = dc \dots 20 \text{ kHz}, \tau_{rise} = 10 \ \mu s$
Temperature drift	1.5 µA/⁰C



Example: The DCCT at GSI synchrotron



Integrating Current Transformer ICT for short Pulses



Short, single pulse at FELs: Too short to be recorded by FCT due to rise time $\tau_{pulse} \ll \tau_{rise} \approx 1$ ns

⇒ depictive statement: 'analog stretching of signal information' yields charges per bunch



ICT operation principle for ps pulses:

- Image current on shell with gap
- Storage of induced charges at C_{int}
- 'Slow' recombination of charges
- Sensing this current with FCT
 ⇒ stretched pulse, length
 independent on input → called ICT
- Torus1 for correct inductance: damped resonant circuit of entire devices
- ▶ Broad bandpass filter ⇒ ringing signal,
 to enlarge sensitivity →called Turbo-ICT





Typical parameter of a Turbo-ICT as used at FELs and Laser Plasma Accelerators:





Transformer: Measurement of the beam's magnetic field

- > Magnetic field is guided by a high μ toroid
- > Types of transformers:

FCT for bunches:Broadband obseravtion, $I_{min} \approx 30 \ \mu\text{A}$, BW $\approx 10 \ \text{kHz} \dots 500 \ \text{MHz}$ DCCT for dc beams:Two toroids + modulation, $I_{min} \approx 1 \ \mu\text{A}$, BW $\approx \text{dc} \dots 20 \ \text{kHz}$ ICT short pulses:Image charge storage \rightarrow analog pulse stretching, $Q_{min} \approx 10 \ \text{fC}$, no timing

Non-destructive, used for all beams

Outline:

- Button type for general purpose
- Linear-cut type for proton synchrotrons
- Cavity BPM for short pulses

A Beam Position Monitor is an non-destructive device for bunched beams

It delivers information about the transverse center of the beam:

- > Trajectory: Position of an individual bunch within a transfer line or synchrotron
- > Closed orbit: Central orbit averaged over a period much longer than a betatron oscillation
- > Single bunch position: Determination of parameters like tune, chromaticity, β -function
- **Remarks**: BPMs have a low cut-off frequency ⇔ dc-beam behavior can't be monitored - The abbreviation **BPM** and pick-up **PU** are synonyms



The image current at the beam pipe is monitored on a high frequency basis i.e. the ac-part given by the bunched beam.



Beam Position Monitor **BPM** is the most frequently used instrument!

For relativistic velocities, the transversal electric field is: $E_{\perp,lab}(t_{lab}) = \gamma E_{\perp,rest}(t_{rest})$



Principle of Signal Generation of a BPMs: off-center Beam



The image current at the wall is monitored on a high frequency basis i.e. ac-part given by the bunched beam. V 000000 Ð Animation by Rhodri Jones (CERN) 19 Peter Forck, ARD ST3, 19th Oct. 2019 **Tutorial: Beam Diagnostics**



The difference voltage between plates gives the beam's center-of-mass \rightarrow **most frequent application**

'Proximity' effect leads to different voltages at the plates:



 $S(\omega,x)$ is called **position sensitivity**, sometimes the inverse is used $k(\omega,x)=1/S(\omega,x)$ **s** is a geometry dependent, non-linear function, which have to be optimized Units: **S**=[%/mm] and sometimes **S**=[dB/mm] or **k**=[mm].

Typical desired position resolution: $\Delta x \approx 0.3 \dots 0.1 \cdot \sigma_x$ of beam width





Button BPM Realization





Courtesy C. Boccard (CERN)

Simulations for Button BPM at Synchrotron Light Sources





Result: non-linearity and *xy*-coupling occur in dependence of button size and position



Frequency range: 1 MHz < f_{rf} < 100 MHz \Rightarrow bunch-length >> BPM length.



651

Technical realization at HIT synchrotron of 46 m length for 7 MeV/u \rightarrow 440 MeV/u BPM clearance: 180x70 mm², standard beam pipe diameter: 200 mm.







Technical realization at HIT synchrotron of 46 m length for 7 MeV/u \rightarrow 440 MeV/u BPM clearance: 180x70 mm², standard beam pipe diameter: 200 mm.



Cavity BPM for FEL-LINACs: Principle





27

Cavity BPM: Example of Realization







Suppression of mono-pole mode: waveguide that couple only to dipole-mode

due to $f_{mono} < f_{cut} < f_{dipole}$



Prototype BPM for ILC Final Focus:

Achieved **resolution** (i.e. 3 BPM relative) of 8.7 nm in a 6×12 mm beam pipe at ATF2 (KEK, Japan)

Remark: - Separated, smaller cavity for monopole mode to have **same** frequency for normalization - For typical proton beams **not** required due to long pulses $t_{pulse} \gg 1 \mu s$

Courtesy of D. Lipka and Y. Honda Phys. Rev. Accel. Beams 11, 062801 (2008)

Intermediate Summary: Comparison of BPM Types (simplified)



Туре	Linear-cut	Button	Cavity	
Usage	p-synchrotron	p-LINACs,	e⁻LINACs (e.g. FEL)	
		all e⁻acc.		
Precaution	Long bunches	Short bunches	Short pulses	
	<i>f_{rf}</i> < 10 MHz	<i>f_{rf}</i> > 10 MHz		
Advantage	Large signal	Simple mechanics	Very sensitive	
	Very linear, no xy- coupling	Broadband	'stores' information	
	For large beams			
Disadvantage	Complex mechanics	Non-linear,	Very complex,	
	horizontal	<i>x-y</i> coupling	High frequency	
	vertical			



- Precise electronics with low drifts to determine position within 10% of beam width

 → online calibration required e.g. permanently by 'pilot tone'
- Best performing digital signal processing to achieve highest resolution

uard rings on

Outline:

- Scintillation screens and Optical Transition Radiation OTR screens
- Wire scanner and SEM-Grid
- Non destructive methods

Proton accelerators: Ionization Profile Monitor, Beam Induced Fluorescence Monitor Electron accelerators: Synchrotron Radiation Monitor

Typical beam sizes:

e⁻-beam: typically Ø 0.01 to 3 mm, protons: typically Ø 1 to 30 mm





Scintillation: Particle's energy loss in matter causes emission of light

 \rightarrow the most direct way of profile observation \rightarrow used from the early days on & daily operation!



Example: Pneumatic drive with Ø70 mm phosphor screen



Some materials and their basic properties:

Name	Туре	Material	Activ.	Max. λ	Decay
Chromox	romox Cera-	Al ₂ O ₃	Cr	700nm	≈ 10ms
Alumina	mics	Al ₂ O ₃	Non	380nm	≈ 10ns
YAG:Ce	Crystal	Y ₃ Al ₅ O ₁₂	Ce	550nm	200ns
LYSO		Lu _{1.8} Y _{.2} SiO ₅	Ce	420nm	40ns
P43	P43 Powder P46 of gains Ø≈10μm on glass	Gd ₂ O ₃ S	Tb	545nm	1ms
P46		Y ₃ Al ₅ O ₁₂	Ce	530nm	300ns
P47		Y ₃ Si ₅ O ₁₂	Ce&Tb	400nm	100ns

These scintillator have about factor 100 different light yield

Properties of a good scintillator:

- \blacktriangleright Optical wavelength \rightarrow standard CCD can be used
- \succ Large dynamic range \rightarrow usable for different currents
- \blacktriangleright Short decay time \rightarrow observation of variations
- \succ Large radiation hardness \rightarrow long lifetime
- \succ Good mechanical properties → typ. size up to Ø 10 cm



Limitation scintillation Screens: High Ionization Density

Observation:

"Smoke-ring" shaped profiles @ XFEL for LYSO:Ce scintillator \rightarrow wrong measure!

Possible explanation:

- Ionization channel related to secondary electron range
- Quenching of fluorescence close to electron track
 - \Rightarrow Important for high flux beam (high current, short bunch & transversally focused
- > Depends on scintillator material, e.g. YAG:Ce might be better



Proton beam image deformation due to:

- High ionization density leads to thermal quenching and saturation
- Radiation damage!

 \Rightarrow Careful choice of scintillation material in dependence of application

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34

Example: XFEL, 14 GeV, 1 nC/bunch, $\sigma \approx 100 \ \mu m$





Optical Considerations for small Beam Measurement



Optics: Old principles & recent realization

- Scheimpflug principle:
 object, image & lens plane coincide in one point
 + tele-centric lens
 - \Rightarrow sharp focus & no image deformation
- Screen thickness ≈100 µm > ≈10 µm beam (thickness given by free-standing crystal)
 ⇒ optimal angle depends on index of refractivity
 ⇒ condition for angle beam ↔ observation







FELs: Suppression of coherent OTR (see below)
 ⇒ optimal angle depends beam energy

Remark: Coherent OTR occurs for high intensities if wavelength \approx bunch size (long.or trans.)

Courtesy S. Gibson RHUL, R. Ischebeck PSI, Phys. Rev. ST Accel. Beams 18, 082802

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Courtesy S. Gibson RHUL, R. Ischebeck PSI, Phys. Rev. ST Accel. Beams 18, 082802



ple: DESY XFEL design



eders DESY, M. Verones ELETTRA

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Scheimpflu
Optical Transition Radiation: Depictive Description



Optical Transition Radiation OTR for a single charge *e*:

Assuming a charge *e* approaches an ideal conducting boundary e.g. metal foil

- Image charge is created by electric field
- Dipole type field pattern
- > Field distribution depends on velocity β and Lorentz factor γ due to relativistic trans. field increase
- Penetration of charge through surface within t < 10 fs: sudden change of source distribution</p>
- Emission of radiation with dipole characteristic



sudden change charge distribution rearrangement of sources ⇔ radiation

Other physical interpretation: Impedance mismatch at boundary leads to radiation

Optical Transition Radiation: Depictive Description



Optical Transition Radiation OTR can be described in classical physics:

approximated formula for normal incidence & in-plane p<u>olarization:</u>



Angular distribution of radiation in optical spectrum:

- \succ Lope emission pattern depends on velocity or Lorentz factor γ
- > Emitted energy i.e. amount of photons scales with $W \propto \beta^2$
- Broad wave length spectrum up to plasma frequency
- \Rightarrow suited for medium and high energy electrons





sudden change charge distribution rearrangement of sources ⇔ radiation

 $\frac{d^2 W}{d\theta \, d\omega} \approx \frac{2e^2\beta^2}{\pi \, c} \cdot \frac{\sin^2\theta \cdot \cos^2\theta}{\left(1 - \beta^2 \cos^2\theta\right)^2}$



OTR is emitted by charged particle passage through a material boundary. Photon distribution: within a solid angle $d\Omega$ and $\frac{dN_{photon}}{d\Omega} = N_{beam} \cdot \frac{2e^2\beta^2}{\pi c} \cdot \log\left(\frac{\lambda_{begin}}{\lambda_{end}}\right) \cdot \frac{\theta^2}{(\gamma^{-2} + \theta^2)^2}$ Wavelength interval λ_{begin} to λ_{end}

- ➢ Detection: Optical 400 nm < λ < 800 nm using image (intensified) CCD
- \blacktriangleright Larger signal for relativistic beam $\gamma >> 1$
- ▶ Low divergence for $\gamma >> 1 \Rightarrow$ large signal
- \Rightarrow well suited for e⁻ beams

 \Rightarrow p-beam only for E_{kin} > 100 GeV $\Leftrightarrow \gamma$ > 100

Advantage:

- \succ Thin foil \Rightarrow low heating & straggling
- 2-dim image visible

Remark: Comparable processes

- Optical diffraction radiation ODR
- Smith–Purcell radiation from gridstructure



coated with $0.1\mu m$ Al

Optical Transition Radiation compared to Scintillation Screen





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Reason: Coherent emission **if** bunch length \approx wavelength (t_{bunch} =2 fs \Leftrightarrow I_{bunch} =600 nm)

or bunch fluctuations ≈ wavelength Parameter reach for most LINAC-based FELs!

Beam parameter: FLASH, 700 MeV, 0.5 nC, with bunch compression OTR screen scint. screen





(c) LuAG screen



prompt emission for OTR and scint. screen
→ coherent and in-coherent OTR

 100 ns delayed emission
 → no OTR as expected (classical process)
 → emission by scint. screen due to lifetime ⇔ correct profile image!

Contrary of M. Yan et al., DIPAC'11 & S. Wesch, DIPAC'11

(b) OTR screen, +100ns delay



OTR: electrodynamic process \Rightarrow beam intensity linear to # photons, high radiation hardness

Scint. Screen: complex atomic process \Rightarrow saturation possible, for some low radiation hardness

OTR: thin foil Al or Al on Mylar, down to 0.25 µm thickness

 \Rightarrow minimization of beam scattering (Al is low Z-material e.g. plastics like Mylar)

Scint. Screen: thickness down to 100 µm inorganic, fragile material, not always radiation hard

OTR: low number of photons (energy dependent) \Rightarrow expensive image intensified CCD

Scint. Screen: large number of photons \Rightarrow simple CCD sufficient

OTR: complex angular photon distribution \Rightarrow resolution limited

Scint. Screen: isotropic photon distribution \Rightarrow simple interpretation

OTR: large γ needed \Rightarrow e⁻-beam with E_{kin} > 100 MeV, proton-beam with E_{kin} > 100 GeV **Scint. Screen**: for all beams

Remark: OTR questionable for LINAC-FEL due to **coherent** light emission .

Beam surface interaction: e⁻ emission proportional to energy loss

Example: 15 wire spaced by 1.5 mm:



At e^- LINACs not used as too large pitch.

SEM-Grid feed-through on CF200:



Slow, linear Wire Scanner



Idea: One wire is scanned through the beam!

Wire diameter 1 μ m < d_{wire} < 100 μ m

Slow, linear scanner are used for:

- Low energy proton cw-beam
- ➢ High resolution for e[−] beam as reference method by de-convolution $\sigma^2_{beam} = \sigma^2_{meas} - d^2_{wire}$ \Rightarrow resolution down to 1 µm range can be reached



Scanners used as reference method!



In a synchrotron <u>one</u> wire is scanned though the beam as fast as possible.

Fast pendulum scanner for synchrotrons; sometimes it is called 'flying wire':





From <u>https://twiki.cern.ch/twiki/</u> bin/viewauth/BWSUpgrade/

1.5

Usage of Flying Wire Scanners at Proton Synchrotrons



Material: Carbon or SiC \rightarrow low Z-material for low energy loss and high temperature. *Thickness*: Down to 10 μ m \rightarrow high resolution.

Detection: High energy secondary particles with a detector like a beam loss monitor

Secondary particles:

Proton beam \rightarrow hadrons shower (π , n, p...) **Electron beam** \rightarrow Bremsstrahlung photons.





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Kinematics of flying wire:

Velocity during passage typically 10 m/s = 36 km/h and

typical beam size \varnothing 10 mm \Rightarrow time for traversing the beam $t \approx$ 1 ms

Actual challenges: Thin wire stability for fast movement with high acceleration,

thermal stability due to large beam power

U. Raich et al., DIPAC 2005

Kinetic energy (MeV)

Comparison between SEM-Grid and <u>slow</u> Wire Scanners

Grid: Measurement at a single moment in time

Scanner: Fast variations can not be monitored

 \rightarrow for pulsed LINACs precise synchronization is needed

Grid: Not adequate at synchrotrons for stored beam parameters

Scanner: At high energy synchrotrons flying wire scanners are nearly non-destructive

Grid: Resolution of a grid is fixed by the wire distance (typically 1 mm)

Scanner: For slow scanners the resolution is about the wire thickness (down to 10 μm)

 \rightarrow used for e--beams having small sizes (down to 10 μ m)

Grid: Needs one electronics channel per wire

 \rightarrow expensive electronics and data acquisition

Scanner: Needs a precise movable feed-through \rightarrow expensive mechanics.

Ionization Profile Monitor at GSI Synchrotron



Non-destructive device for proton synchrotron:
> beam ionizes the residual gas by electronic stopping
> gas ions or e⁻ accelerated by E -field ≈1 kV/cm

spatial resolved single particle detection



Typical vacuum pressure:

Transfer line: N₂ 10⁻⁸...10⁻⁶ mbar \cong 3.10⁸...3.10¹⁰ cm⁻³ Synchrotron: H₂ 10⁻¹¹...10⁻⁹ mbar \cong 3.10⁵...3.10⁷ cm⁻³ Realization at GSI synchrotron: One monitor per plane





The realization for the heavy ion storage ring ESR at GSI: Realization at GSI synchrotron:



Ionization Profile Monitor Realization







Electron Detection and Guidance by Magnetic Field







e⁻ detection in an external magnetic field \rightarrow cyclotron radius $r_C = \frac{mv_\perp}{eB}$ for $E_{kin,\perp} = 10 \text{ eV} \& B = 0.1 \text{ T} \Rightarrow r_c \approx 100 \text{ }\mu\text{m}$ E_{kin} from atomic physics, $\approx 100 \ \mu m$ resolution of MCP

Time-of-flight: $\approx 1 - 2$ ns $\Rightarrow 2 - 3$ cycles. **B-field**: Dipole with large aperture \rightarrow IPM is expensive & large device!

Ion detection mode:

Example for Space Charge Broadening at IPMs



Example for SIS18, length C = 216 m: 500 MeV/u with typical SIS18 parameters H_2^+ detection:

Extr.: $\sigma_{long} = 25 \text{ ns}$ $\sigma_{trans} = 2.3 \text{ mm}$ $t_{drift} = 220 \pm 15 \text{ ns}$ \Rightarrow broadening for $N > 10^{10}$ /bunch e⁻ detection:

 t_{drift} = 4.5±1 ns \Rightarrow no broadening









⇒ high intensities needs guiding magnetic field of $B \approx 100$ mT







Magnetic field for electron guidance:

Maximum image distortion:

5% of beam width $\Rightarrow \Delta B/B < 1\%$

Challenges:

- High B-field homogeneity of 1%
- Clearance up to 50 cm
- Correctors compensating by beam steering
- Insertion length up to 2.5 m incl. correctors

Actual Challenges for IPM:

- MCP single particle detector lifetime and calibration Alternative: Silicon pixel detector
- Turn-by-turn readout due to low signal Goal: e.g. control of transverse injection matching
- > Correction of space charge broadening e.g. by machine learning for image reconstruction **Electron beams**: Resolution of 50 μ m is insufficient, but sometimes used for photon beams



B = 250 mT
Gap 220 mm
Profile 32 strips
2.5 mm width

Beam Induced Fluorescence BIF Monitor



Detecting *photons* from residual gas molecules, e.g. Nitrogen

 $N_2 + Ion \rightarrow (N_2^+)^* + Ion \rightarrow N_2^+ + \gamma + Ion$

390 nm< λ< 470 nm

emitted into solid angle Ω to camera single photon detection scheme

Advantage:

- Nearly no installation inside vacuum
- High resolution (here 0.2 mm/pixel)
 can be matched to application by optics
 Commercial in
- Commercial Image Intensifier
 Disadvantage:
- \blacktriangleright Low signal strength, $\approx 10^{-4}$ of IPM
- ➢ Pressure bump up to 10⁻⁶ mbar required

Usage:

At high power proton LINACs,

e.g. GSI-UNILAC, ESS normal conducting $E_{kin} \leq$ 90 MeV

Actual challenge:

- Best performing gases, e.g. neutral Ne at 585 nm
- Space charge influence correction



Beam: Ar^{10+} at 4.7 MeV/u, I=2.5 mA, 10^{11} ppp, p= 10^{-5} mbar

54



An electron bent (i.e. accelerated) by a dipole magnet emit synchrotron light



Realization of a Synchrotron Radiation Monitor

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Extracting out of the beam's plane by a (cooled) mirror

- \rightarrow Focus to a slit + wavelength filter for optical wavelength
- ightarrow Image by sensitive camera

Example: ESRF monitor from dipole with bending radius 22 m (blue or near UV)



Diffraction Limit of Synchrotron Light Monitor





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Different techniques are suited for different beam parameters:

e⁻-beam: typically Ø 0.01 to 3 mm, protons: typically Ø 1 to 30 mm

Intercepting ↔ non-intercepting methods (proton beams might have high beam intensity)

Direct observation of electrodynamics processes:

- > Synchrotron radiation monitor: non-destructive $\rightarrow e^-$ -beams, complex
- > OTR screen: nearly non-destructive, large relativistic γ needed $\rightarrow e^-$ -beams mainly

Detection of secondary photons, electrons or ions:

- > Scintillation screen: destructive, large signal, simple setup \rightarrow all beams
- > IPM & BIF: non-destructive, expensive, limited resolution \rightarrow for high intensity protons

Wire based electronic methods:

- SEM-grid: partly destructive, large signal and dynamic range, limited resolution
- > Wire scanner: partly destructive, large signal and dynamics, high resolution, slow scan.

Outline:

- Bunch length at non-relativistic proton LINACs
- Bunch length at FEL LINACs
 - electro-optical methods
 - transverse deflecting cavities

Remark: At proton synchrotrons the accelerating frequency is normally $f_{rf} \lesssim 10$ MHz

 \Rightarrow bunch shape can be measured by Fast Current Transformer



Bunch Structure at low *E_{kin}*: Not possible with Pick-Ups



Pick-ups are used for:

- precise for bunch-center relative to rf
- course image of bunch shape

But:

For $\beta \ll 1 \rightarrow \text{long.} E$ -field significantly modified:





Example: Calculation of transverse eclectic field



Example: Comparison pick-up – particle counter:

Ar beam of 1.4 MeV/u (β = 5.5%) , f_{rf} = 108 MHz



 \Rightarrow the pick-up signal is insensitive to bunch 'fine-structure'

Bunch Structure using secondary Electrons for low Ekin Protons





SEM: secondary electron multiplier

Bunch Structure using secondary Electrons for low Ekin Protons





62 \rightarrow conclusion



FELs \rightarrow **bunch length below 1 ps is achieved**, i.e. below the resolution of streak camera \succ Short laser pulses with $t \approx 10$ fs and electro-optical modulator **Electro optical modulator:** birefringent, rotation angle depends on external electric field **Relativistic electron bunches**: transverse field E_{\perp} and E_{\perp} are carries the time information.



Hardware of a compact EOS Scanning Setup





Example: Bunch length at FLASH 100 fs bunch duration = 30 μm length



B. Steffen et al, DIPAC 2009B. Steffen et al., Phys. Rev. AB 12, 032802 (2009)



Transversal deflection of the bunch i.e. time-to-space conversion



Size of the streak given by

$$\sigma_{y} = \sqrt{\sigma_{y0}^{2} + R_{35} \cdot k \cdot \sigma_{z}^{2}}$$

k is determined by the rf-power $k = \frac{2\pi e \cdot U_{rf}}{\lambda_{rf}E}$



From D. Xiang et al., IPAC'12

Bunch Length by rf-Deflection: Hardware



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66 \rightarrow conclusion





Diagnostics is required for operation and development of accelerators

Several categories of demands leads to different installations:

- Quick, non-destructive measurements leading to a single number or simple plots
- Complex instrumentation used for hard malfunction and accelerator development
- > Automated measurement and control of beam parameters i.e. feedback

The goal and a clear interpretation of the results is a important design criterion.

General comments:

- > Quite different technologies are used, based on various physics processes
- > Accelerator development goes parallel to diagnostics development

Further instruments and diagnostic methods:

- Beam Loss Monitors, bunch shape monitors, laser-based methods for e⁻ & H⁻, luminosity monitors....
- Diagnostics for closed orbit & lattice parameters, Schottky analysis.....

Thank you for your attention!



Backup slides

Laser Scanner: Principle for H⁻ Beams







Y. Liu (SNS) et al., NIM A 238, 241 (2010), R.Connolly et al., Proc. LINAC'02

Laser Scanner: Detection Scheme for H⁻ at SNS-LINAC



SNS installation:

- Nd:YAG (λ_{lab} =1064 nm, 100 mJ, 7ns)
- One of 9 stations is served at a time
- \blacktriangleright Laser with spot size: 10 to 50 μ m
- \succ e⁻ separation by **B** \approx 20 mT
- Detection with Faraday Cup



Electron collector

Dipole magnet

Y. Liu (SNS) et al., NIM A 238, 241 (2010),Y. Liu (SNS) et al., Phys. Rev Accel. Beams 16, 2013)





'Inverse' Compton Scattering by photon scattered at high energy electron:

Calculation: Regular Compton scattering in e⁻ rest frame & Lorentz Transformation to lab-frame \Rightarrow Increase of photon energy by γ^2 for 90° scattering $hv_{sc} = 2\gamma^2 \cdot hv_0$ i.e. up to GeV Detection by γ -ray detector e.g. thick scintillator



Laser Wire Scanner at PETRA III at DESY: Installation





Peter Forck, ARD ST3, 19th Oct. 2019
Model for Signal Treatment of capacitive BPMs



At a resistor \boldsymbol{R} the voltage \boldsymbol{U}_{im} from the image current is measured.

Goal: Connection from beam current to signal strength by transfer impedance $Z_t(\omega)$

in frequency domain: $U_{im}(\omega) = R \cdot I_{im}(\omega) = Z_t(\omega) \cdot I_{beam}(\omega)$



Example of Transfer Impedance for Proton Synchrotron



The high-pass characteristic for typical synchrotron BPM:



Large signal strength for long bunches \rightarrow high impedance Smooth signal transmission important for short bunches \rightarrow 50 Ω **Remark:** For $\omega \rightarrow 0$ it is $Z_t \rightarrow 0$ i.e. **no** signal is transferred from dc-beams e.g.

- de-bunched beam inside a synchrotron
- for slow extraction through a transfer line



Test of different scintillators

Tpy. scintillators \leftrightarrow Phosphor powder \leftrightarrow ceramics

Example: Irradiation with ions at GSI

> Light yield:

Very different brightness (here factor 1000) Still linear with beam current even for large doses

> Profile:

Most materials show correct results

Deviation understood and possible cures discussed

Accelerators: ⇒ Material choice matched to beam Radiation hardness tests

Example: Irradiation with 0.5 MeV/u and 300 MeV/u

- Damage by irritation depends strongly on ion type and energy
- Model calculations discussed with experts

Accelerators:

 \Rightarrow Important finding for target diagnostics at SNS or ESS

Corutesy B. Walasek-Höhne GSI



X-ray Pin-Hole Camera



The diffraction limit is $\Rightarrow \sigma \cong 0.6 \cdot (\lambda^2 / \rho)^{1/3} \Rightarrow$ shorter wavelength by X-rays.



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76 \rightarrow conclusion

Secondary Electron Emission by Ion Impact



Energy loss of ions in metals close to a surface:

Closed collision with large energy transfer: \rightarrow fast e⁻ with $E_{kin} >> 100 \text{ eV}$

Distant collision with low energy transfer : \rightarrow slow e⁻ with $E_{kin} \leq 10 \text{ eV}$

- \rightarrow 'diffusion' & scattering with other e⁻: scattering length $L_s \approx 1 10$ nm
- \rightarrow at surface \approx 90 % probability for escape

Secondary **electron yield** and energy distribution comparable for all metals!

 \Rightarrow **Y** = const. * dE/dx (Sternglass formula)

